



## CLUSTER DETECTOR TEST REPORT

### CLUSTER DETECTOR No. 8

Test carried on 05.12.11 – 07.12.11

Ch.	HEX	U <sub>op</sub> [V]	U <sub>op</sub> – 500 V		U <sub>op</sub>			
			FWHM [keV]	$\frac{FWTM}{FWHM}$	1332 keV			122 keV
					FWHM [keV]	$\frac{FWTM}{WFHM}$	Pos. [Ch.]	FWHM [keV]
A	93	4000	1.95	n.c.	2.01	n.c.	6298	
B	44	4500	2.08	n.c.	1.90	n.c.	6376	
C	179	4500	2.18	n.c.	2.11	n.c.	6550	
D	48	4000	2.12	n.c.	2.08	n.c.	6689	
E	166	4000	2.16	n.c.	2.12	n.c.	6152	
F	81	4000	2.15	n.c.	2.12	n.c.	6533	
G	47	4000	2.11	n.c.	2.11	n.c.	7382	

Operational Temperature: -173.9 °C

Date: 07.12.2011

Tested by:  
/I.Kojouharov/

**Assembly and test remarks:**

Regular test after assembly atRIKEN.

**Test Equipment:**

HV – ORTEC 660

Main Amplifier – ORTEC 671,  $\tau = 6 \mu\text{s}$ , Gain 100 x 0.72

ADC – 4801A (RIKEN), MCA - PC98B

**Source -  $^{60}\text{Co}$**